

**Proceedings of the  
3<sup>rd</sup> International Workshop on  
Evaluation of  
Ontology based  
Tools  
(EON 2004)**



## Organization Committee

York Sure (Contact Person), Institute AIFB at University of Karlsruhe (DE)

Oscar Corcho, Intelligent Software Components, S.A. (ES)

Jérôme Euzenat, INRIA (FR)

Todd Hughes, Lockheed Martin (US)

## Program Committee

Dean Allemang, TopQuadrant, Inc. (US), [dalleman@topquadrant.com](mailto:dalleman@topquadrant.com)

Bill Andersen, Ontology Works, Inc. (US), [andersen@ontologyworks.com](mailto:andersen@ontologyworks.com)

Sean Bechhofer, University of Manchester (UK), [seanb@cs.man.ac.uk](mailto:seanb@cs.man.ac.uk)

Richard Benjamins, Intelligent Software Components, S.A. (ES), [rbenjamins@isoco.com](mailto:rbenjamins@isoco.com)

John Davies, BT (UK), [john.nj.davies@bt.com](mailto:john.nj.davies@bt.com)

AnHai Doan, University of Illinois (US), [anhai@cs.uiuc.edu](mailto:anhai@cs.uiuc.edu)

Christian Fillies, SemTalk (DE), [cfillies@semtalk.com](mailto:cfillies@semtalk.com)

Fausto Giunchiglia, University of Trento (IT), [fausto@dit.unitn.it](mailto:fausto@dit.unitn.it)

Asunción Gómez-Pérez, Universidad Politécnica de Madrid (ES), [asun@fi.upm.es](mailto:asun@fi.upm.es)

Kouji Kozaki, Osaka University (JP), [kozaki@ei.sanken.osaka-u.ac.jp](mailto:kozaki@ei.sanken.osaka-u.ac.jp)

Natasha F. Noy, Stanford University (US), [noy@smi.stanford.edu](mailto:noy@smi.stanford.edu)

Henrik Oppermann, Ontoprise (DE), [oppermann@ontoprise.de](mailto:oppermann@ontoprise.de)

Norman Sadeh, Carnegie Mellon University (US), [sadeh@cs.cmu.edu](mailto:sadeh@cs.cmu.edu)

Heiner Stuckenschmidt, Vrije Universiteit Amsterdam (NL), [heiner@cs.vu.nl](mailto:heiner@cs.vu.nl)

Rudi Studer, University of Karlsruhe (DE), [studer@aifb.uni-karlsruhe.de](mailto:studer@aifb.uni-karlsruhe.de)

Raphael Troncy, INA (France), for Institute National of Audiovisual,

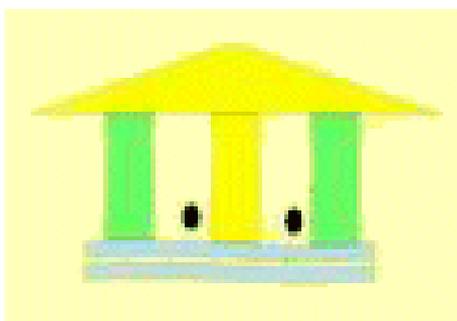
[Raphael.Troncy@ina.fr](mailto:Raphael.Troncy@ina.fr)

Mike Uschold, Boeing (US), [michael.f.uschold@boeing.com](mailto:michael.f.uschold@boeing.com)

Takahira Yamaguchi, Keio University (JP), [yamaguti@ae.keio.ac.jp](mailto:yamaguti@ae.keio.ac.jp)

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## Introduction

In the series of “Evaluation of Ontology-based Tools” workshops we intend to bring together researchers and practitioners from the fastly developing research areas “ontologies” and “Semantic Web”. Currently the semantic web attracts researchers from all around the world. Numerous tools and applications of semantic web technologies are already available and the number is growing fast. However, deploying large scale ontology solutions typically involves several separate tasks and requires applying multiple tools. Therefore pragmatic issues such as interoperability are key if industry is to be encouraged to take up ontology technology rapidly.

The main aim of this workshop is therefore to encourage and stimulate discussions about the evaluation of ontology-based tools. For the future this effort might lead to future benchmarks and certifications.

This workshop follows the previously held EON2002 (held at the EKAW 2002) and EON2003 (held at the ISWC 2003).

The EON workshops are associated with experiments. Initially they corresponded to the OntoWeb SIG on tools discussions, now this evolved into the Knowledge Web, in particular the workpackage on Heterogeneity for the experiment for this workshop. The general question is how to evaluate ontology related technologies. To break down this rather complex task into a pragmatic one, the group decided to focus first on ontology engineering environments (OEE) as a starting point in EON2002 and EON2003. These tools are rather common and widely used by the Semantic Web Community and some of the participating members were even tool provider themselves. During the first experiment, design issues and limitations of state-of-the-art OEEs were being evaluated. This time the focus was on ontology alignment, all participants were challenged to provide a set of mappings between given ontological fragment. The aim was to compare the alignments given by all participants to give an overview on state-of-the-art ontology alignment tools and their abilities.

Further information about the workshop and the experiment can be found at: <http://km.aifb.uni-karlsruhe.de/ws/eon2004/>

We thank all members of the program committee, additional reviewers, authors, experiment participants and local organizers for their efforts.

We are looking forward to having fruitful discussions at the workshop!

York Sure, Oscar Corcho, Jérôme Euzenat, Todd Hughes

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